Application/Control No.	Applicar Reexam

nt(s)/Patent under nination DE JONG ET AL.

09/892,684

Examiner

Art Unit

Thuy N. Pardo 2165

SEARCHED				
Class	Subclass	Date	Examiner	
FIF	101	7/21/06	TP	
i	102	/		
	103 R	:		
\bigvee	104.1			
717	104.1	\bigvee	V	
•				

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
77	100	7/21/06	TP	
,'	101			
	102			
	103R			
	104.1			
FIF	150	\bigvee	V	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
TEEL	7/21/06	TP	